


Search Notes 	Application/Control No. 10599310	Applicant(s)/Patent Under Reexamination VOLOSHIN ET AL.
	Examiner Young J Kim	Art Unit 1637

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SEARCH NOTES		
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Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB) - see enclosed for text search strategy	9/29/2010	/YJK/
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